

X'Pert HighScore	X'Pert HighScore Report	date: 10/20/23
PANalytical		for internal use only

Fantastic report on Document1



Distribution:

Name	Function	0.1	0.5	1.0
N.N.-999	Masterking Group Manager (MGM)	✓		
N.N.-998	Product Ontwikkelt Manager (POM)	✓		
N.N.-1	(AS)			✓
N.N.-2	(DS)			✓
N.N.-3	(BS)			✓
T.P.	Supervisor All Coding			✓

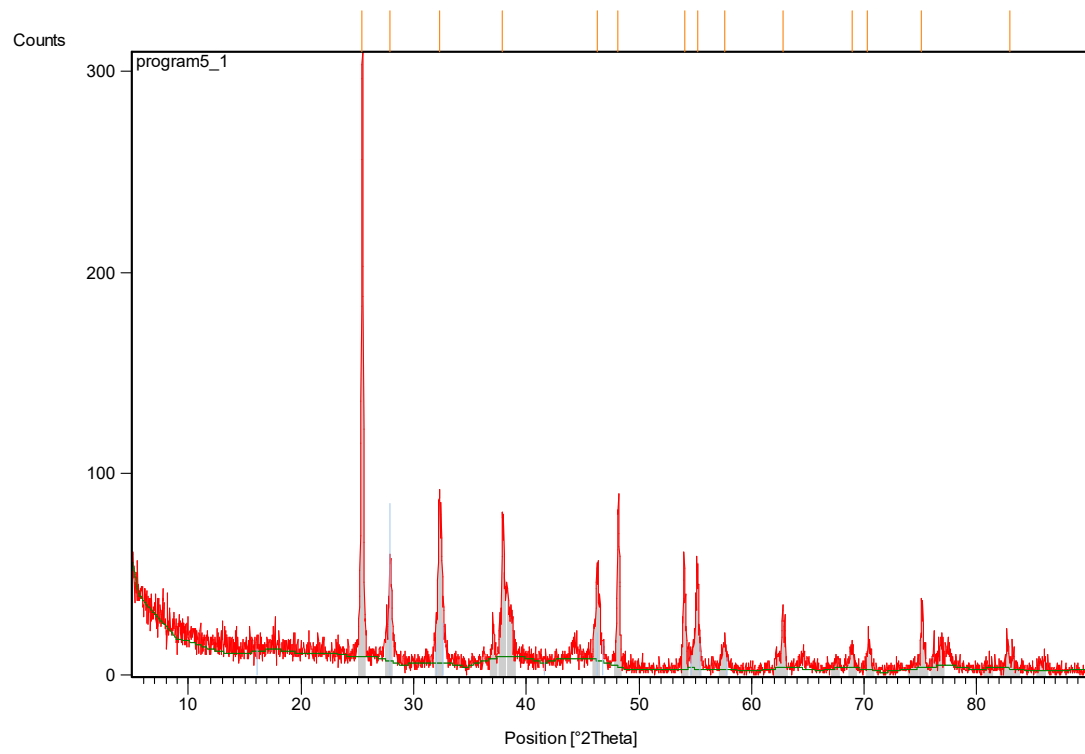
Last saved by CWI	Draft	file: program5 1.doc	rev: 1
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Anchor Scan Parameters: (Bookmark1)

Dataset Name	program5_1
File name	E:\X'Pert Data\2023\7\khaled el attar\program5_1.xrdml
Comment	Configuration=Stage Flat Samples, Owner=r, Creation
date=2/28/2009 2:36:26 PM	Goniometer=PW3050/60 (Theta/Theta); Minimum step size
2Theta:0.001; Minimum step size	Omega:0.001
	Sample stage=PW3071/xx Bracket
	Diffraction system=XPRT-PRO
	Measurement program=program5, Owner=r, Creation
date=12/12/2004 11:02:06 AM	
Measurement Date / Time	7/13/2023 10:11:01 AM
Operator	cwi
Raw Data Origin	XRD measurement (*.XRDML)
Scan Axis	Gonio
Start Position [$^{\circ}2\text{Th.}$]	5.0150
End Position [$^{\circ}2\text{Th.}$]	89.9750
Step Size [$^{\circ}2\text{Th.}$]	0.0300
Scan Step Time [s]	0.8500
Scan Type	Continuous
Offset [$^{\circ}2\text{Th.}$]	0.0000
Divergence Slit Type	Fixed
Divergence Slit Size [$^{\circ}$]	0.4785
Specimen Length [mm]	10.00
Receiving Slit Size [mm]	0.1000
Measurement Temperature [$^{\circ}\text{C}$]	25.00
Anode Material	Cu
K-Alpha1 [\AA]	1.54060
K-Alpha2 [\AA]	1.54443
K-Beta [\AA]	1.39225
K-A2 / K-A1 Ratio	0.50000
Generator Settings	30 mA, 40 kV
Diffraction Type	0000000000005545
Diffraction Number	0
Goniometer Radius [mm]	240.00
Dist. Focus-Diverg. Slit [mm]	91.00
Incident Beam Monochromator	No
Spinning	No

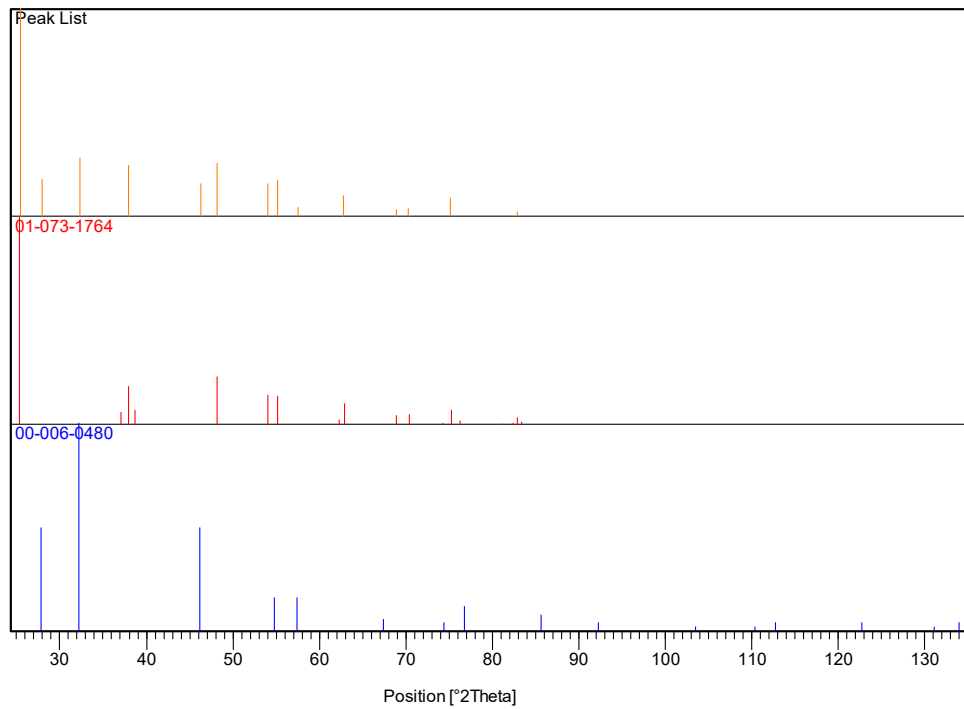
Graphics: (Bookmark2)

Peak List: (Bookmark 3)

Pos. [°2Th.]	Height [cts]	FWHM [°2Th.]	d-spacing [Å]	Rel. Int. [%]	Tip width [°2Th.]	Matched by
25.4282	294.02	0.1771	3.50289	100.00	0.2125	01-073-1764
27.9393	51.89	0.2362	3.19350	17.65	0.2834	00-006-0480
32.3090	81.99	0.3542	2.77088	27.89	0.4251	00-006-0480
37.8764	72.28	0.1771	2.37542	24.58	0.2125	01-073-1764
46.2968	45.27	0.4133	1.96110	15.40	0.4959	00-006-0480
48.1503	75.29	0.1771	1.88985	25.61	0.2125	01-073-1764
54.0300	46.50	0.2362	1.69726	15.82	0.2834	01-073-1764
55.1796	50.89	0.2362	1.66459	17.31	0.2834	01-073-1764
57.5827	12.51	0.4723	1.60071	4.25	0.5668	00-006-0480
62.7931	28.94	0.3542	1.47984	9.84	0.4251	01-073-1764
68.8952	10.12	0.3542	1.36292	3.44	0.4251	01-073-1764
70.3194	10.57	0.3542	1.33876	3.59	0.4251	01-073-1764
75.1116	25.78	0.1771	1.26480	8.77	0.2125	01-073-1764
82.9333	6.21	0.8640	1.16327	2.11	1.0368	01-073-1764

Identified Patterns List: (Bookmark4)

Visible	Ref. Code	Score	Compound Name	Displacement [°2Th.]	Scale Factor	Chemical Formula
*	01-073-1764	65	Anatase, syn	0.000	0.668	Ti O ₂
*	00-006-0480	57	Chlorargyrite, syn	0.000	0.228	Ag Cl

Plot of Identified Phases: (Bookmark 5)

Document History: (Bookmark 6)

Insert Measurement:

- File name = "program5_1.xrdml"
- Modification time = "7/19/2023 9:53:48 AM"
- Modification editor = "cwi"

Default properties:

- Measurement step axis = "None"
- Internal wavelengths used from anode material: Copper (Cu)
- Original K-Alpha1 wavelength = "1.54060"
- Used K-Alpha1 wavelength = "1.54060"
- Original K-Alpha2 wavelength = "1.54443"
- Used K-Alpha2 wavelength = "1.54443"
- Original K-Beta wavelength = "1.39225"
- Used K-Beta wavelength = "1.39225"
- Incident beam monochromator = "No"
- Dist. focus to div. slit = "91.00000"
- Irradiated length = "10.00000"
- Spinner used = "No"
- Receiving slit size = "0.10000"
- Linear detector mode = "None"
- Length linear detector = "2"
- Step axis value = "0.00000"
- Offset = "0.00000"
- Sample length = "10.00000"
- Modification time = "7/19/2023 9:53:48 AM"
- Modification editor = "cwi"

Determine Background:

- Correction method = "Automatic"
- Bending factor = "5"
- Use smoothed input data = "Yes"
- Granularity = "20"
- Add to net scan = "Nothing"
- Modification time = "2/22/2001 10:17:43 AM"
- Modification editor = "PANalytical"

Search Peaks:

- Minimum significance = "2.00"
- Minimum tip width = "0.01"
- Maximum tip width = "1.00"
- Peak base width = "2.00"
- Method = "Minimum 2nd derivative"
- Modification time = "2/20/2001 11:55:18 AM"
- Modification editor = "PANalytical"

Search & Match:

- Data source = "Profile and peak list"
- Restriction = "None"
- Scoring schema = "Multi phase"
- Auto residue = "Yes"

- Match intensity = "Yes"
- Demote unmatched strong = "Yes"
- Allow pattern shift = "No"
- Two theta shift = "0"
- Identify = "Yes"
- Max. no. of accepted patterns = "5"
- Minimum score = "27"
- Search depth = "6"
- Min. new lines / total lines = "40"
- Minimum new lines = "3"
- Minimum scale factor = "0.06"
- Modification time = "2/16/2001 11:03:07 AM"
- Modification editor = "PANalytical"